

Abstract

This invention is characterized to include a discrete analysis frequency width change specifying process for specifying in a particular frequency range a change in the discrete high-speed Fourier transform (FFT) analysis frequency width and a modeling process for allocating different discrete FFT analysis frequency widths to the specified frequency range and to a frequency range other than the specified frequency range and performing modeling. The EMI analysis method of this invention reflects on the gate level power supply current calculation the influence of decoupling by resistance, capacitance and inductance of the power supply and ground, thereby making it possible to evaluate the EMI of LSIs in simulation in a realistic time and to provide efficient EMI countermeasures through supporting the identifying of the EMI causing locations.